

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/672,863 EDNEY ET AL.	
		Examiner	Art Unit	Page 1 of 1 James Kish 3737

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0100864	08-2002	Wake, Robert H.	250/208.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Slepicka et al., Stabilized Non-Linear Regression for Interferogram Analysis, 10 August 1995, Applied Optics, Vol. 34, No. 23, pages 5039-5044
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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